

**Search Notes**

Applicant/Contractor

10/789,886

Examiner

Frederick C. Nicolas

Applicant(s)/Patent under  
Reexamination

MEYER ET AL.

Art Unit

3754

**SEARCHED**

Class	Subclass	Date	Examiner
222	566-568	8/27/2006	FN
222	173,181.2	8/27/2006	FN
222	196,196.1	8/27/2006	FN
222	575,180	8/27/2006	FN
222	610,475	8/27/2006	FN
222	465.1,183	8/27/2006	FN
222	105	8/27/2006	FN
224	148.2,274	8/27/2006	FN
224	148.4,401	8/27/2006	FN
206	217,477	8/27/2006	FN
206	564	8/27/2006	FN
248	310,318	8/27/2006	FN
248	311.2	8/27/2006	FN
248	205.1	8/27/2006	FN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
222	568	8/27/2006	FN
222	105	8/27/2006	FN
222	181.2	8/27/2006	FN
222/465.1 222/566 222/575 224/148.4		8/27/2006	FN

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated search thru east including text search. Interference search also conducted.	8/27/2006	FN